



OEG

Optik
Elektronik
Gerätetechnik

IMM200 - Inspection Microscope with Measuring software



Microscope

The microscope works with bright field incident light illumination. This makes it ideally suited for the inspection and measurement of silicon wafers, solar cells, mask substrates and any other reflecting objects. It is equipped with infinity corrected high quality objectives 5x, 10x, 20x 50x. The visual magnification results with eye piece 10x to 50x, 100x, 200x and 500x.

Wafer Table

IMM 200 is equipped with a manually x/y-stage with (200 x 200) mm effective stroke. Each position can be clamped, then the fine positioning by micrometer screws is possible. The vacuum wafer chuck can be rotated by exact 90° without vacuum switch off. Additionally an angle fine positioning of the chuck, using a micrometer screw, is possible. The upgrade with a motorized inspection stage is possible.

On inquiry OEG GmbH can supply the adaption of a wafer loader or a wafer robot.

Attachments

The microscope can be used either for visual inspection only or both in connection with cameras. For use with camera, a TV-tube and different TV-adaptions are available.

Software

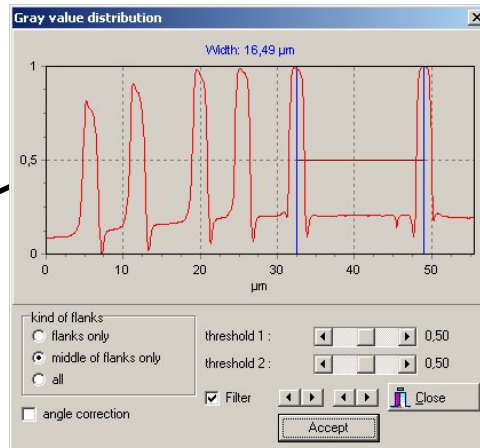
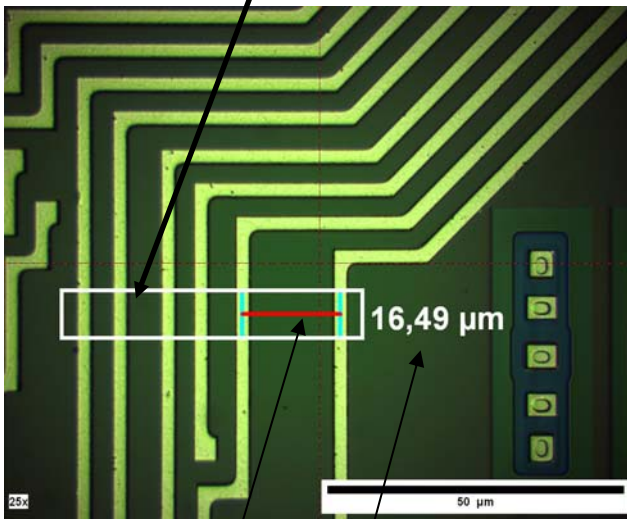
If the microscope is equipped with camera, the measuring software COMEF is the ideal solution for easy and accurate measurements and the documentation of the measuring results in protocols or directly in the digital image. COMEF provides powerful measuring functions, based on grey value processing with subpixel accuracy. COMEF can work with numerous kinds of cameras using Twain and WDM-Interface. It has direct connection to a special type of camera with a resolution range up to 5 MPixel. Microscopes with analogue CCD-camera can be retrofitted with COMEF using a frame grabber for video digitizing.





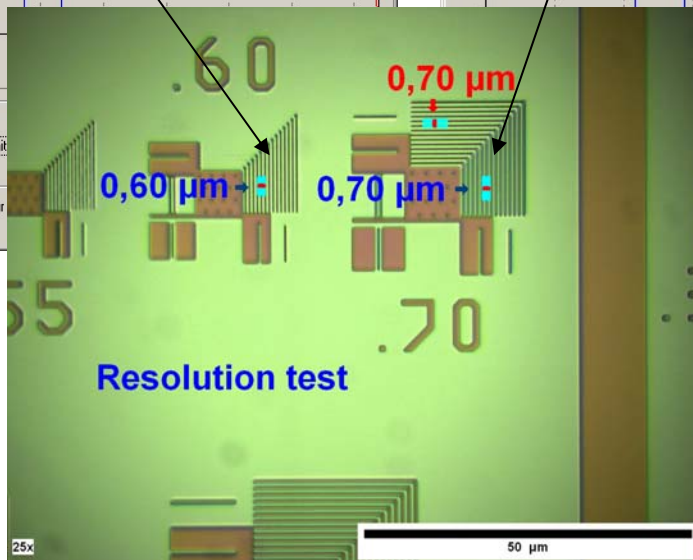
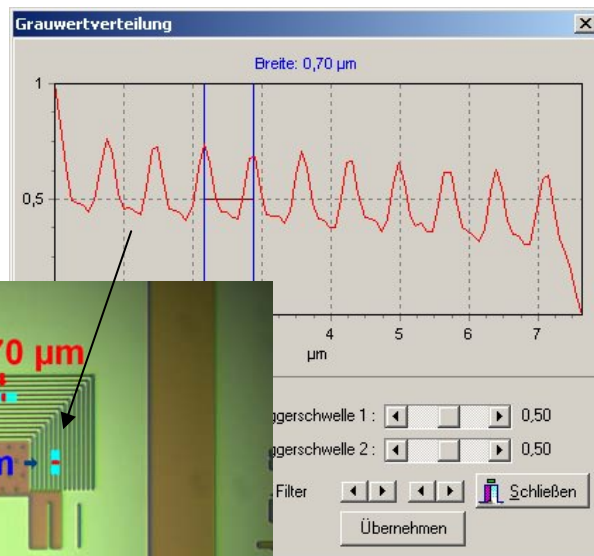
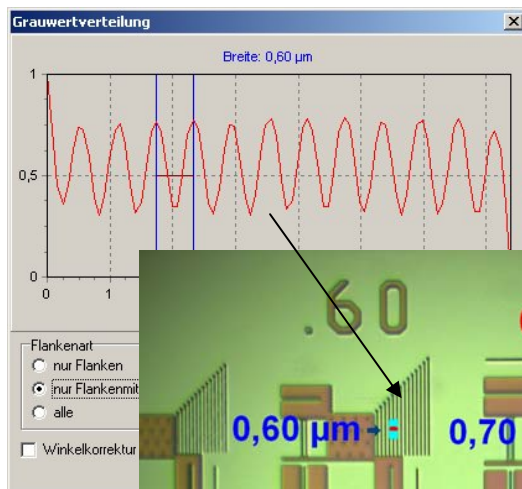
Examples for software features

White: Measuring field, which is evaluated



Grey value distribution inside the measuring field.
The measurement takes place using this grey values and defined trigger threshold.

Measuring marks and -values can be inserted in the digital image easily.



Standard- and special solutions

On the basis of the standard solution special solutions can be developed in respect to the microscope magnification, -illumination, the table size and table operation (manual or motorized).

Also the software can be adapted to special requirements.

The software is available as full demo version on www.oeggmbh.com.

There are also shown some examples for special measuring microscopes.